



Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DKT. NO.  
635.46415X00SERIAL NO.  
10/589,118

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

APPLICANT

P. LINDER

FILING DATE  
August 11, 2006

GROUP

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation /Abstract	
						Yes	No
	AM						
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	AO						
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	AV	
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Examiner		Date Considered
/Sean Hagan/		09/25/2007

Sheet 1 of 1

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 635.46415X00	SERIAL NO. 10/589118 <del>To be assigned</del>
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		<b>FILING DATE</b> August 11, 2006	<b>GROUP</b>

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